INF	ORMATION CITATION		ATTY. DOCKET NO. 2336-257		U.S. PATENT APPLICATION NO. 10/811,808			
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FOREIGN PATENT DOCUMENTS								
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.